

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/615,050	EILERT, SEAN E.	
Examiner		Art Unit		Page 1 of 1
Hiep T. Nguyen		2187		

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	C	US-2004/0155298	08-2004	Bhattacharyya, Arup	257/378
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**NON-PATENT DOCUMENTS**

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